- Low $r_{DS(on)} \dots 1.3 \Omega$ Typ
- Avalanche Energy . . . 75 mJ
- Eight Power DMOS Transistor Outputs of 250-mA Continuous Current
- 1.5-A Pulsed Current Per Output
- Output Clamp Voltage up to 45 V
- Low Power Consumption

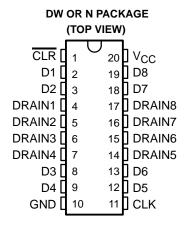
description

The TPIC6273 is a monolithic high-voltage high-current power logic octal D-type latch with DMOS transistor outputs designed for use in systems that require relatively high load power. The device contains a built-in voltage clamp on the outputs for inductive transient protection. Power driver applications include relays, solenoids, and other medium-current or high-voltage loads.

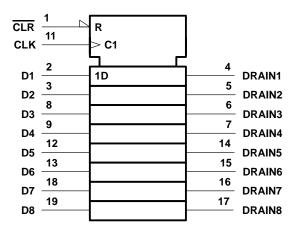
The TPIC6273 contains eight positive-edgetriggered D-type flip-flops with a direct clear input. Each flip-flop features an open-drain power DMOS transistor output.

When clear (CLR) is high, information at the D inputs meeting the setup time requirements is transferred to the DRAIN outputs on the positive-going edge of the clock pulse. Clock triggering occurs at a particular voltage level and is not directly related to the transition time of the positive-going pulse. When the clock input (CLK) is at either the high or low level, the D input signal has no effect at the output. An asynchronous CLR is provided to turn all eight DMOS-transistor outputs off.

The TPIC6273 is characterized for operation over the operating case temperature range of -40° C to 125°C.



logic symbol†



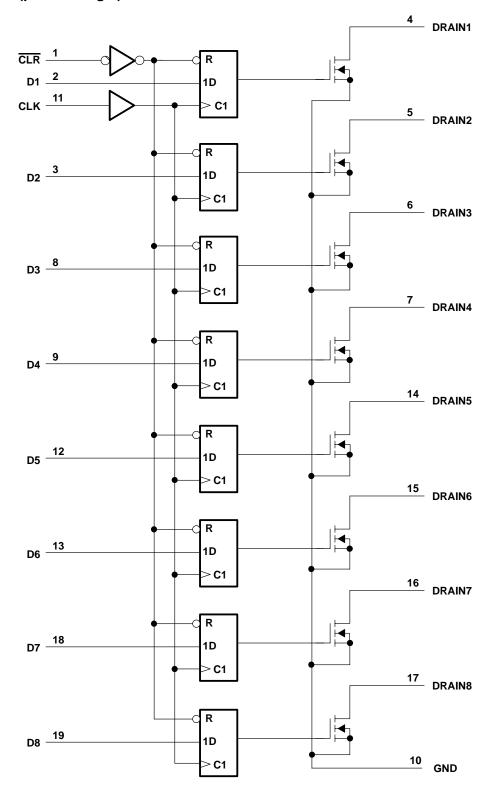
† This symbol is in accordance with ANSI/IEEE Standard 91-1984 and IEC Publication 617-12.

FUNCTION TABLE (each channel)

INPUTS			OUTPUT
CLR	CLK	D	DRAIN
L	Χ	Х	Н
Н	\uparrow	Н	L
Н	\uparrow	L	Н
Н	L	Χ	Latched

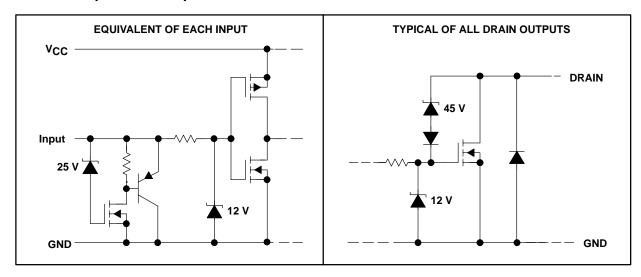
H = high level, L = low level, X = irrelevant

logic diagram (positive logic)





schematic of inputs and outputs



absolute maximum ratings over recommended operating case temperature range (unless otherwise noted) $\!\!\!\!^{\dagger}$

Logic supply voltage, V _{CC} (see Note 1)	7 V
Logic input voltage range, V _I	0.3 V to 7 V
Power DMOS drain-to-source voltage, V _{DS} (see Note 2)	45 V
Continuous source-drain diode anode current	1 A
Pulsed source-drain diode anode current	2 A
Pulsed drain current, each output, all outputs on, I _{Dn.} T _A = 25°C (see Note 3)	750 mA
Continuous drain current, each output, all outputs on, I _{Dn} , T _A = 25°C	
Peak drain current single output, I _{DM} ,T _A = 25°C (see Note 3)	
Single-pulse avalanche energy, E _{AS} (see Figure 4)	
Avalanche current, I _{AS} (see Note 4)	1 A
Continuous total power dissipation	
Operating virtual junction temperature range, T _J	
Storage temperature range, T _{stq}	
Lead temperature 1,6 mm (1/16 inch) from case for 10 seconds	

[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTES: 1. All voltage values are with respect to GND.

- 2. Each power DMOS source is internally connected to GND.
- 3. Pulse duration \leq 100 μ s, duty cycle \leq 2%
- 4. DRAIN supply voltage = 15 V, starting junction temperature (T_{JS}) = 25°C, L = 100 mH, I_{AS} = 1 A (see Figure 4).

DISSIPATION RATING TABLE

PACKAGE	$T_A \le 25^{\circ}C$ POWER RATING	DERATING FACTOR ABOVE T _A = 25°C	T _A = 125°C POWER RATING
DW	1125 mW	9.0 mW/°C	225 mW
N	1150 mW	9.2 mW/°C	230 mW



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recommended operating conditions over recommended operating temperature range (unless otherwise noted)

	MIN	MAX	UNIT
Logic supply voltage, V _{CC}	4.5	5.5	V
High-level input voltage, VIH	0.85 V _{CC}		V
Low-level input voltage, V _{IL}		0.15 V _{CC}	V
Pulsed drain output current, T _C = 25°C, V _{CC} = 5 V (see Notes 3 and 5)	-1.8	1.5	Α
Setup time, D high before CLK↑, t _{SU} (see Figure 2)	10		ns
Hold time, D high after CLK↑, th (see Figure 2)	15		ns
Pulse duration, t _W (see Figure 2)	25		ns
Operating case temperature, T _C	-40	125	°C

electrical characteristics, V_{CC} = 5 V, T_{C} = 25°C (unless otherwise noted)

PARAMETER		TEST CONDITIONS			MIN	TYP	MAX	UNIT
V(BR)DSX	Drain-source breakdown voltage	$I_D = 1 \text{ mA}$			45			V
V_{SD}	Source-drain diode forward voltage	$I_F = 250 \text{ mA},$	See Note 3			0.85	1	V
liΗ	High-level input current	$V_{CC} = 5.5 \text{ V},$	$V_I = V_{CC}$				1	μΑ
I _{IL}	Low-level input current	$V_{CC} = 5.5 \text{ V},$	V _I = 0				-1	μΑ
Icc	Logic supply current	I _O = 0,	All inputs low			15	100	μΑ
I _N	Nominal current	$V_{DS(on)} = 0.5$ $I_{N} = I_{D}$	5 V, T _C = 85°C	See Notes 5, 6, and 7		250		mA
la av	Off-state drain current	V _{DS} = 40 V				0.05	1	
DSX		$V_{DS} = 40 \text{ V},$	T _C = 125°C			0.15	5	μΑ
		$I_D = 250 \text{ mA},$	V _{CC} = 4.5 V			1.3	2	
rDS(on)	Static drain-source on-state resistance	$I_D = 250 \text{ mA},$ $V_{CC} = 4.5 \text{ V}$	$T_{C} = 125^{\circ}C,$	See Notes 5 and 6 and Figures 8 and 9		2	3.2	Ω
		$I_D = 500 \text{ mA},$	$V_{CC} = 4.5 \text{ V}$			1.3	2	

switching characteristics, $V_{CC} = 5 \text{ V}$, $T_{C} = 25^{\circ}\text{C}$

PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
t _{PLH}	Propagation delay time, low-to-high-level output from CLK			625		ns
tPHL	Propagation delay time, high-to-low-level output from CLK	$C_L = 30 \text{ pF}, \qquad I_D = 250 \text{ mA},$		150		ns
t _r	Rise time, drain output	See Figures 1, 2, and 10		675		ns
tf	Fall time, drain output			400		ns
ta	Reverse-recovery-current rise time	$I_F = 250 \text{ mA}, \qquad \text{di/dt} = 20 \text{ A/}\mu\text{s},$		100		no
t _{rr}	Reverse-recovery time	See Notes 5 and 6 and Figure 3		300		ns

NOTES: 3. Pulse duration \leq 100 μ s, duty cycle \leq 2%

- 5. Technique should limit $T_J T_C$ to 10°C maximum.
- 6. These parameters are measured with voltage-sensing contacts separate from the current-carrying contacts.
- 7. Nominal current is defined for a consistent comparison between devices from different sources. It is the current that produces a voltage drop of 0.5 V at $T_C = 85$ °C.

thermal resistance

PARAMETER		TEST CONDITIONS	MIN	MAX	UNIT	
$R_{\theta JA}$	Thermal resistance, junction-to-ambient	DW package	All 8 outputs with equal power		111	°C/W
		N package	All 8 outputs with equal power		108	C/VV



PARAMETER MEASUREMENT INFORMATION

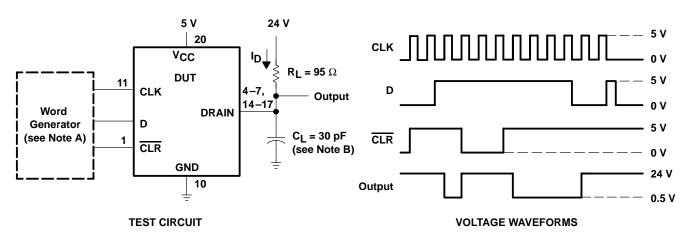


Figure 1. Resistive Load Normal Operation

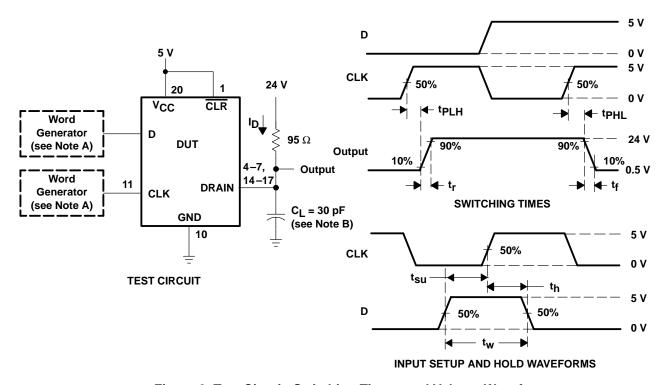
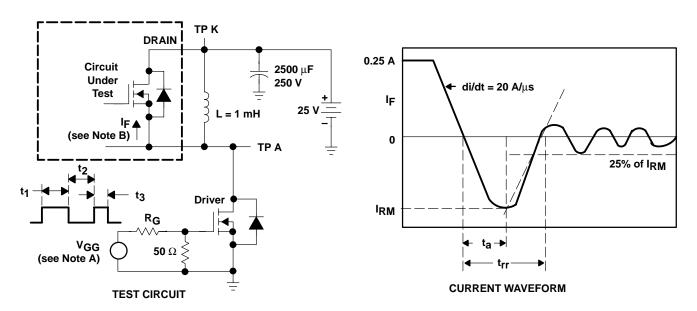


Figure 2. Test Circuit, Switching Times, and Voltage Waveforms

NOTES: A. The word generator has the following characteristics: $t_{\Gamma} \le 10$ ns, $t_{W} = 300$ ns, pulsed repetition rate (PRR) = 5 KHz, $Z_{\Omega} = 50 \ \Omega$.

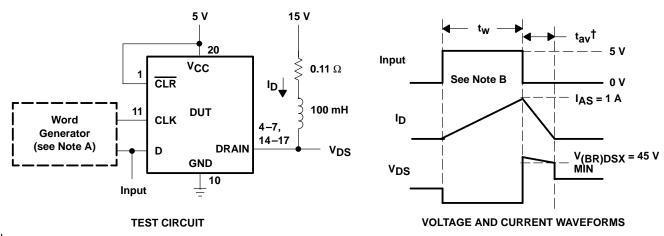
B. C_L includes probe and jig capacitance.

PARAMETER MEASUREMENT INFORMATION



- NOTES: A. The V_{GG} amplitude and R_G are adjusted for di/dt = 20 A/ μ s. A V_{GG} double-pulse train is used to set I_F = 0.25 A, where t₁ = 10 μ s, t₂ = 7 μ s, and t₃ = 3 μ s.
 - B. The DRAIN terminal under test is connected to the TP K test point. All other terminals are connected together and connected to the TP A test point.

Figure 3. Reverse-Recovery-Current Test Circuit and Waveforms of Source-Drain Diode



† Non-JEDEC symbol for avalanche ftime.

NOTES: A. The word generator A has the following characteristics: $t_{\Gamma} \le$ 10 ns, $t_{\tilde{f}} \le$ 10 ns, $Z_{\tilde{O}} =$ 50 Ω .

B. Input pulse duration, t_W , is increased until peak current $I_{AS} = 1$ A. Energy test is defined as $E_{AS} = I_{AS} \times V_{(BR)DSX} \times t_{aV}/2 = 75$ mJ, where t_{aV} = avalanche time.

Figure 4. Single-Pulse Avalanche Energy Test Circuit and Waveforms



TYPICAL CHARACTERISTICS

Figure 5

MAXIMUM CONTINUOUS
DRAIN CURRENT OF EACH OUTPUT
vs
NUMBER OF OUTPUTS CONDUCTING

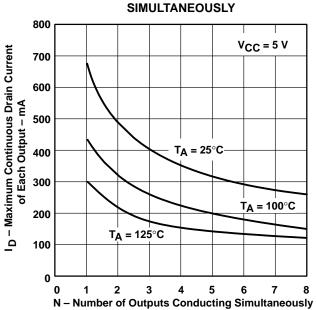


Figure 6

MAXIMUM PEAK DRAIN CURRENT OF EACH OUTPUT

VS NUMBER OF OUTPUTS CONDUCTING SIMULTANEOUSLY

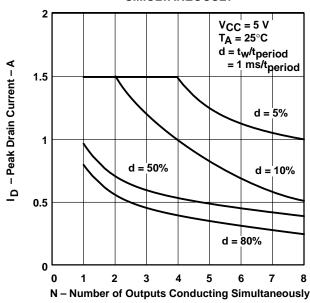
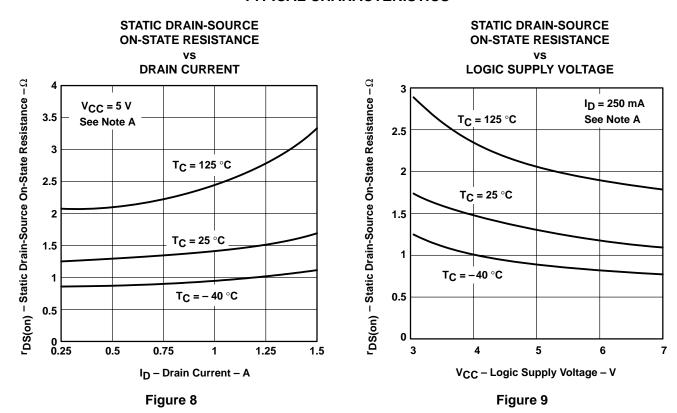
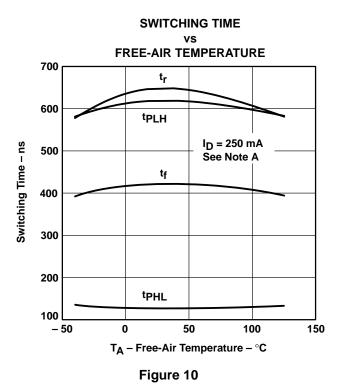


Figure 7



TYPICAL CHARACTERISTICS





NOTE A: Technique should limit $T_J - T_C$ to 10°C maximum.



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